

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/650,913	FURUKAWA ET AL.	AL.	
Examiner	Art Unit		
IOHN PAK	1616		

	SEARCHED				
Class	Subclass	Date	Examiner		
424	618 630 641	11/05			
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<i>514 523</i>	772.3	1			

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
WEST-See Printout	9/05	90	